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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/699,121	10/31/2003	Stefan Schneidewind	A36066 - 066340.0179	4997
21003	7590	03/16/2006	EXAMINER	
BAKER & BOTTS 30 ROCKEFELLER PLAZA NEW YORK, NY 10112			NGUYEN, TUNG X	
			ART UNIT	PAPER NUMBER
			2829	

DATE MAILED: 03/16/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary

Application No.

10/699,121

Applicant(s)

SCHNEIDEWIND ET AL.

Examiner

Tung X. Nguyen

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 12 January 2006.
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-21 is/are pending in the application.
- 4a) Of the above claim(s) 10-21 is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-9 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 31 October 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☐ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____

- 4) ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: _____

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

2. Claims 1-9 are rejected under 35 U.S.C. 102(b) as being anticipated by Sato (u.s.p 6,124,725).

As to claim 1, Sato discloses in Figs. 1-4, a substrate (W of figure 1) is mounted on a chuck (11) and makes contact with contact needles (12A); wherein contact needle being connected to enable testing of electrical characteristics of circuit elements on the semiconductor substrate (W of figure 1); and mechanically accelerating the mounted semiconductor substrate in contact with the needles; and measuring the electrical characteristics of the circuit elements during the mechanical acceleration of the mounted semiconductor substrate while it is in contact with the contact needles (X-Y-Z direction driving mechanism 24, col. 4, lines 1-20 and 50-55).

As to claims 2-3, Sato discloses in Figs. 1-4, wherein the substrate is subjected to acceleration, which is initially positive and is then negative down to the stationary state, wherein the acceleration comprising a linear acceleration (via 24 of figure 1).

As to claim 4, Sato discloses in Figs. 1-4, the linear acceleration takes place in a direction, which is parallel to the upper face of the substrate (via 24).

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As to claim 5, Sato discloses in Figs 1-4, the linear acceleration take place in a direction, which is perpendicular to the upper face of the substrate (12, and 24 of figure 1).

As to claim 6, Sato discloses in Figs. 1-4, the acceleration represents a rotary acceleration (θ direction figure 1, col. 8, lines 65-68) with respect to a rotation axis which is perpendicular to an upper face of the substrate (W of figure 1)

As to claim 7, Sato discloses in Figs. 1-4, the acceleration is repeated (via 24 and repeated after testing DUT).

As to claim 8, Sato discloses the substrate (W of figure 1) is caused to oscillate mechanically (figs 1-4).

As to claim 9, Sato discloses in Fig. 7, the acceleration is produced by a mechanical blow (57, 44).

Response to Arguments

3. Applicant's arguments filed 1/12/06 have been fully considered but they are not persuasive.

Applicant's filed response with RCE filed on 1/12/06. It is still not overcome the final rejection on 8/23/05.

In re pages 6-7, to Applicant argues that Sato does not show "mechanically accelerating the mounted semiconductor substrate while it is in contact with the contact needles" or "measuring the electrical characteristics of the circuit elements during the mechanical acceleration of the mounted semiconductor substrate while it is in contact with the contact needles".

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In response, the Examiner respectfully disagrees with Applicant about the issue for the following the reasons: a wafer testing apparatus (10) comprising a main chuck (11) which is movable in X, Y, Z and θ directions and adjustable in temperature; a contactor 12 having a large number of probe terminals 12A which are simultaneously brought into contact with electrode pads of chips formed on a wafer W placed on the main chuck during testing (Figs. 1-4, col. 4, lines 8-15). Therefore, Sato does show measuring the electrical characteristics of the circuit elements during the mechanical acceleration of the mounted semiconductor substrate while it is in contact with the contact needles.

Conclusion

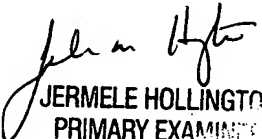
4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tung X. Nguyen whose telephone number is (571) 272-1967. The examiner can normally be reached on 8:30am-5:00pm M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TN
3/15/06


JERMELE HOLLINGTON
PRIMARY EXAMINER
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03/15/06